Designer's™ Data Sheet

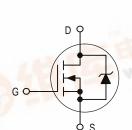
TMOS E-FET ™ High Energy Power FET

N-Channel Enhancement-Mode Silicon Gate

This advanced high voltage TMOS E-FET is designed to withstand high energy in the avalanche mode and switch efficiently. This new high energy device also offers a drain-to-source diode with fast recovery time. Designed for high voltage, high speed switching applications such as power supplies, PWM motor controls and other inductive loads, the avalanche energy capability is specified to eliminate the guesswork in designs where inductive loads are switched and offer additional safety margin against unexpected voltage transients.

- Avalanche Energy Capability Specified at Elevated Temperature
- Low Stored Gate Charge for Efficient Switching
- Internal Source-to-Drain Diode Designed to Replace External Zener Transient Suppressor — Absorbs High Energy in the Avalanche Mode
- Source-to-Drain Diode Recovery Time Comparable to Discrete Fast Recovery Diode





MTP5N40E

Motorola Preferred Device

TMOS POWER FET 5.0 AMPERES 400 VOLTS RDS(on) = 1.0 OHM



CASE 221A-06, Style 5 TO-220AB

MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	400	Vdc
Drain–Gate Voltage (RGS = 1.0 M Ω)	VDGR	400	Vdc
Gate–Source Voltage — Continuous — Non–repetitive	Vgs Vgsm	±20 ±40	Vdc Vpk
Drain Current — Continuous — Pulsed	I _D	5.0 12	Adc
Total Power Dissipation @ T _C = 25°C Derate above 25°C	P _D	75 0.6	Watts W/°C
Operating and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C

UNCLAMPED DRAIN-TO-SOURCE AVALANCHE CHARACTERISTICS (TJ < 150°C)

Single Pulse Drain-to-Source Avalanche Energy — T _J = 25°C	W _{DSR} (1)	290	mJ
$-T_{J} = 100^{\circ}C$		46	
Repetitive Pulse Drain-to-Source Avalanche Energy	W _{DSR} (2)	7.4	

THERMAL CHARACTERISTICS

Thermal Resistance — Junction to Case — Junction to Ambient	R _θ JC R _θ JA	1.67 62.5	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	TL	260	°C

⁽¹⁾ $V_{DD} = 50 \text{ V}, I_{D} = 5.0 \text{ A}$

REYS'c.com

Designer's Data for "Worst Case" Conditions — The Designer's Data Sheet permits the design of most circuits entirely from the information presented. SOA Limit curves — representing boundaries on device characteristics — are given to facilitate "worst case" design.

E-FET and Designer's are trademarks of Motorola, Inc. TMOS is a registered trademark of Motorola, Inc.

Preferred devices are Motorola recommended choices for future use and best overall value.



⁽²⁾ Pulse Width and frequency is limited by T_J(max) and thermal response

Cha	Symbol	Min	Тур	Max	Unit	
OFF CHARACTERISTICS		•	•	•	•	
Drain-to-Source Breakdown Voltag (V _{GS} = 0, I _D = 250 μAdc)	V(BR)DSS	400	_	_	Vdc	
Zero Gate Voltage Drain Current (V _{DS} = 400 V, V _{GS} = 0) (V _{DS} = 320 V, V _{GS} = 0, T _J = 125	IDSS	_	_	0.25 1.0	mAdc	
Gate-Body Leakage Current, Forw	IGSSF	_	_	100	nAdc	
Gate-Body Leakage Current, Reve	erse (V _{GSR} = 20 Vdc, V _{DS} = 0)	IGSSR	_	_	100	nAdc
ON CHARACTERISTICS*		•		1	•	
Gate Threshold Voltage (V _{DS} = V _{GS} , I _D = 250 μAdc) (T _J = 125°C)	VGS(th)	2.0 1.5	_ _	4.0 3.5	Vdc	
Static Drain-Source On-Resistance	e (V _{GS} = 10 Vdc, I _D = 2.5 Adc)	R _{DS(on)}	_	0.8	1.0	Ohm
Drain–Source On–Voltage ($V_{GS} = 10 \text{ Vdc}$) ($I_{D} = 5.0 \text{ A}$) ($I_{D} = 2.5 \text{ A}$, $T_{J} = 100^{\circ}\text{C}$)		VDS(on)	_ _	_	6.2 5.0	Vdc
Forward Transconductance (VDS =	15 Vdc, I _D = 2.5 Adc)	9FS	2.0	_	_	mhos
DYNAMIC CHARACTERISTICS		•		•		
Input Capacitance		C _{iss}	_	775	_	pF
Output Capacitance	$(V_{DS} = 25 \text{ V}, V_{GS} = 0, \\ f = 1.0 \text{ MHz})$	C _{oss}	_	96	_	
Transfer Capacitance		C _{rss}	_	22	_	
SWITCHING CHARACTERISTICS*				•		
Turn-On Delay Time		td(on)	_	24	-	ns
Rise Time	$(V_{DD} = 250 \text{ V}, I_{D} \approx 5.0 \text{ A}, R_{G} = 12 \Omega, R_{L} = 50 \Omega,$	t _r	_	34	_	
Turn-Off Delay Time	$V_{GS(on)} = 10 \text{ V}$	td(off)	_	60	_	
Fall Time	` ,	t _f	_	36	_	
Total Gate Charge		Qg	_	27	32	nC
Gate-Source Charge	$(V_{DS} = 320 \text{ V}, I_{D} = 5.0 \text{ A}, V_{GS} = 10 \text{ V})$	Q _{gs}	_	3.5	_	
Gate-Drain Charge	30 1 /	Q _{gd}	_	14	_	
SOURCE-DRAIN DIODE CHARACT	ERISTICS*					
Forward On-Voltage		V _{SD}	_	_	1.4	Vdc
Forward Turn-On Time	$(I_S = 5.0 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s})$	ton		**		ns
Reverse Recovery Time		t _{rr}	_	_	660	
INTERNAL PACKAGE INDUCTANC	E			_	_	
Internal Drain Inductance (Measured from the contact screw on tab to center of die) (Measured from the drain lead 0.25" from package to center of die)		L _d		3.5 4.5		nH
Internal Source Inductance (Measured from the source lead 0.25" from package to source bond pad)		L _S	_	7.5	_	

^{*} Indicates Pulse Test: Pulse Width = 300 μs Max, Duty Cycle \leq 2.0%. ** Limited by circuit inductance.

TYPICAL ELECTRICAL CHARACTERISTICS

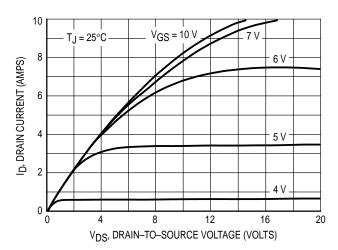


Figure 1. On-Region Characteristics

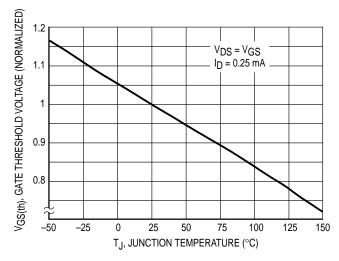


Figure 2. Gate-Threshold Voltage Variation
With Temperature

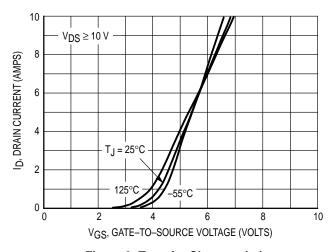


Figure 3. Transfer Characteristics

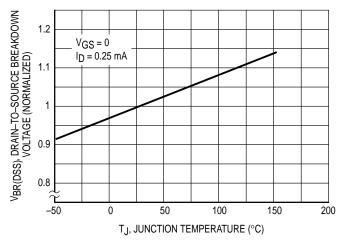


Figure 4. Breakdown Voltage Variation With Temperature

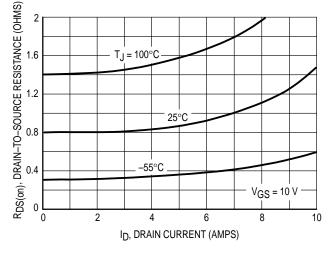


Figure 5. On-Resistance versus Drain Current

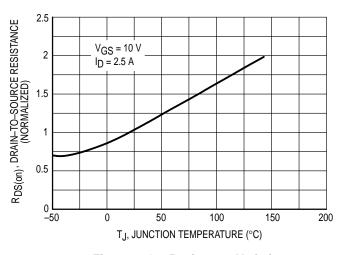


Figure 6. On–Resistance Variation
With Temperature

SAFE OPERATING AREA INFORMATION

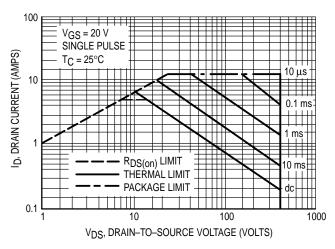


Figure 7. Maximum Rated Forward Biased Safe Operating Area

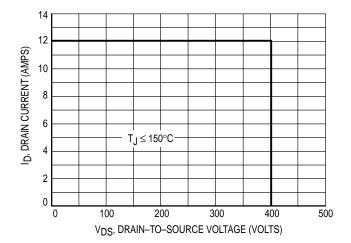


Figure 8. Maximum Rated Switching Safe Operating Area

FORWARD BIASED SAFE OPERATING AREA

The FBSOA curves define the maximum drain—to—source voltage and drain current that a device can safely handle when it is forward biased, or when it is on, or being turned on. Because these curves include the limitations of simultaneous high voltage and high current, up to the rating of the device, they are especially useful to designers of linear systems. The curves are based on a case temperature of 25°C and a maximum junction temperature of 150°C. Limitations for repetitive pulses at various case temperatures can be determined by using the thermal response curves. Motorola Application Note, AN569, "Transient Thermal Resistance—General Data and Its Use" provides detailed instructions.

SWITCHING SAFE OPERATING AREA

The switching safe operating area (SOA) of Figure 8 is the boundary that the load line may traverse without incurring damage to the MOSFET. The fundamental limits are the peak current, IDM and the breakdown voltage, V(BR)DSS. The switching SOA shown in Figure 8 is applicable for both turnon and turnoff of the devices for switching times less than one microsecond.

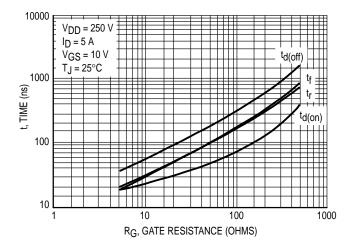


Figure 9. Resistive Switching Time Variation versus Gate Resistance

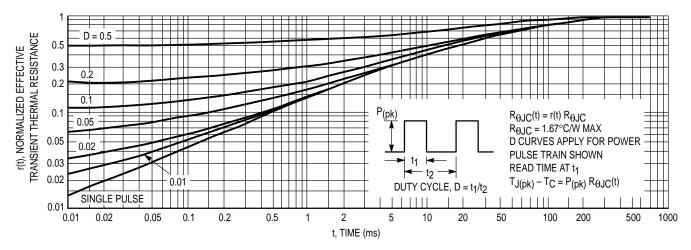
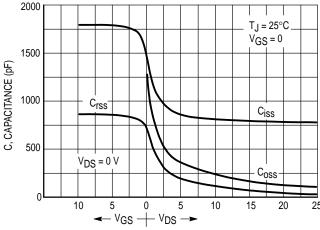


Figure 10. Thermal Response



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 11. Capacitance Variation

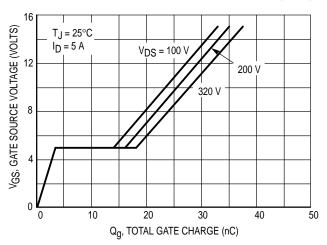


Figure 12. Gate Charge versus Gate—To—Source Voltage

COMMUTATING SAFE OPERATING AREA (CSOA)

The Commutating Safe Operating Area (CSOA) of Figure 14 defines the limits of safe operation for commutated source—drain current versus re—applied drain voltage when the source—drain diode has undergone forward bias. The curve shows the limitations of IFM and peak VDS for a given rate of change of source current. It is applicable when waveforms similar to those of Figure 11 are present. Full or half-bridge PWM DC motor controllers are common applications requiring CSOA data.

Device stresses increase with increasing rate of change of source current so dl_S/dt is specified with a maximum value. Higher values of dl_S/dt require an appropriate derating of l_{FM} , peak V_{DS} or both. Ultimately dl_S/dt is limited primarily by device, package, and circuit impedances. Maximum device stress occurs during $t_{\Gamma\Gamma}$ as the diode goes from conduction to reverse blocking.

 $V_{DS(pk)}$ is the peak drain-to-source voltage that the device must sustain during commutation; I_{FM} is the maximum forward source-drain diode current just prior to the onset of commutation.

 V_R is specified at 80% of $V_{(BR)DSS}$ to ensure that the CSOA stress is maximized as I_S decays from I_{RM} to zero.

RGS should be minimized during commutation. T_J has only a second order effect on CSOA.

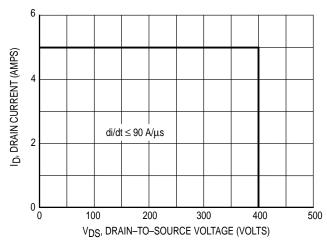


Figure 13. Commutating Safe Operating Area (CSOA)

Stray inductances in Motorola's test circuit are assumed to be practical minimums. dV_{DS}/dt in excess of 10 V/ns was attained with dl_{S}/dt of 400 A/ μ s.

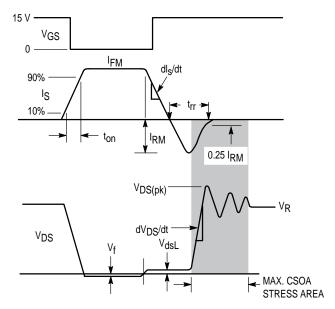


Figure 15. Commutating Waveforms

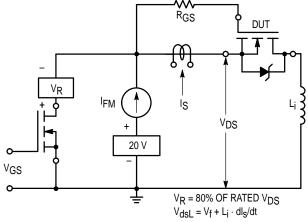


Figure 14. Commutating Safe Operating Area Test Circuit

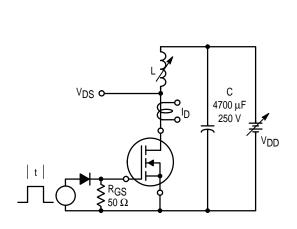


Figure 16. Unclamped Inductive Switching Test Circuit

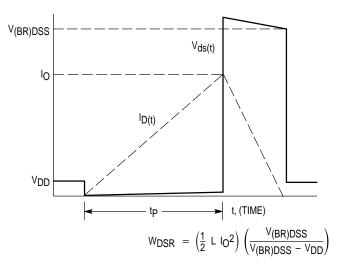
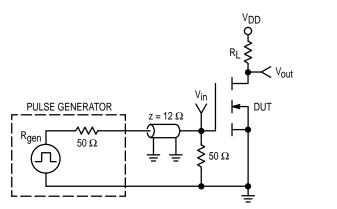


Figure 17. Unclamped Inductive Switching Waveforms

RESISTIVE SWITCHING



* Note: The Mirror is shorted to the Kelvin terminal for this test.

Figure 18. Switching Test Circuit

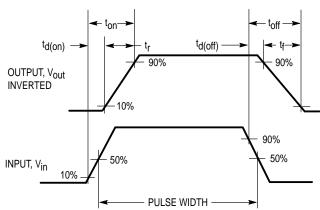
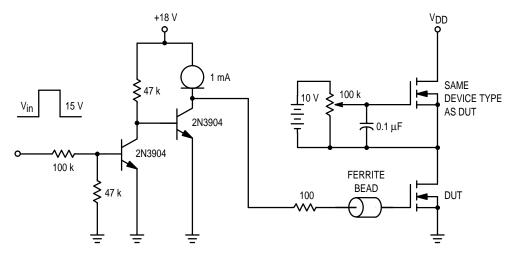


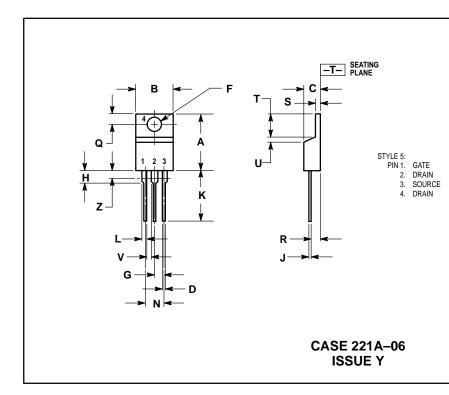
Figure 19. Switching Waveforms



 $V_{\mbox{in}}$ = 15 $V_{\mbox{pk}};$ PULSE WIDTH \leq 100 $\mu \mbox{s},$ DUTY CYCLE \leq 10%

Figure 20. Gate Charge Test Circuit

PACKAGE DIMENSIONS



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.
 3. DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE ALLOWED.

	INCHES MILLIMETERS			IFTERS
DIM	MIN	MAX	MIN	MAX
Α	0.570	0.620	14.48	15.75
В	0.380	0.405	9.66	10.28
С	0.160	0.190	4.07	4.82
D	0.025	0.035	0.64	0.88
F	0.142	0.147	3.61	3.73
G	0.095	0.105	2.42	2.66
Н	0.110	0.155	2.80	3.93
7	0.018	0.025	0.46	0.64
K	0.500	0.562	12.70	14.27
L	0.045	0.060	1.15	1.52
N	0.190	0.210	4.83	5.33
ø	0.100	0.120	2.54	3.04
R	0.080	0.110	2.04	2.79
S	0.045	0.055	1.15	1.39
Т	0.235	0.255	5.97	6.47
5	0.000	0.050	0.00	1.27
٧	0.045		1.15	
Z		0.080		2.04

Motorola reserves the right to make changes without further notice to any products herein. Motorola makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does Motorola assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages. "Typical" parameters can and do vary in different applications. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. Motorola does not convey any license under its patent rights nor the rights of others. Motorola products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the Motorola product could create a situation where personal injury or death may occur. Should Buyer purchase or use Motorola products for any such unintended or unauthorized application, Buyer shall indemnify and hold Motorola and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that Motorola was negligent regarding the design or manufacture of the part. Motorola and A pare registered trademarks of Motorola, Inc. is an Equal Opportunity/Affirmative Action Employer.

How to reach us: USA/EUROPE: Motorola Literature Distribution; P.O. Box 20912; Phoenix, Arizona 85036. 1–800–441–2447

JAPAN: Nippon Motorola Ltd.; Tatsumi-SPD-JLDC, Toshikatsu Otsuki, 6F Seibu-Butsuryu-Center, 3–14–2 Tatsumi Koto-Ku, Tokyo 135, Japan. 03–3521–8315

MFAX: RMFAX0@email.sps.mot.com – TOUCHTONE (602) 244–6609 INTERNET: http://Design-NET.com

HONG KONG: Motorola Semiconductors H.K. Ltd.; 8B Tai Ping Industrial Park, 51 Ting Kok Road, Tai Po, N.T., Hong Kong. 852–26629298

